

In re application of: W. Thomas Novak

Attorney Docket No.: NIKOP037

Application No.: 10/764,377

Examiner: H. Nguyen

Filed: January 22, 2004

Group: 2851

Title: INTERFEROMETER SYSTEM FOR MEASURING A HEIGHT OF WAFER STAGE

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the U.S. Postal Service with sufficient postage as first-class mail on June 20, 2005 in an envelope addressed to the Commissioner for Patents, P.O. Box 1450 Alexandria, VA 22313-1450.

Signed:

SEPARATE LETTER TO THE OFFICIAL DRAFTSMAN REQUESTING ENTERING OF FORMAL DRAWINGS (MPEP 608.02(p))

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Dear Sir:

In response to the objections made due to informalities in the original drawings (or to corrections approved by the Examiner), enclosed are substitute (formal) drawings for the aboveidentified patent application. If the Draftsman has any question concerning these drawings, he or she is respectfully requested to contact the undersigned.

Respectfully submitted,

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